

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

| | | | | | |
|--|---|----|---|--------------------------|-------------------|
| Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary) | | | | Complete if Known | |
| | | | | Application Number | NOT YET ASSIGNED |
| | | | | Filing Date | December 15, 2003 |
| | | | | First Named Inventor | Kie Y. Ahn |
| | | | | Art Unit | N/A |
| | | | | Examiner Name | Not Yet Assigned |
| Sheet | 1 | of | 1 | Attorney Docket Number | M4065.0383/P383-B |

| U.S. PATENT DOCUMENTS | | | | | |
|-----------------------|--------------------------|--|--------------------------------|--|---|
| Examiner Initials* | Cite No. ¹ | Document Number | Publication Date MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear |
| | | Number-Kind Code ² (if known) | | | |
| LA | AA | 5,429,978 | 07-04-1995 | Lu et al.* | |
| | AB | 4,575,700 | 03-1986 | Dalman* | |
| | AC | 5,426,399 | 06-1995 | Matsubayashi et al.* | |
| | AD | 5,447,887 | 09-05-1995 | Filipiak et al.* | |
| | AE | 5,849,625 | 12-15-1998 | Hsue, et al.* | |
| | AF | 6,140,688 | 10-31-2000 | Gardner et al.* | |
| | AG | 6,255,698 | 07-03-2001 | Gardmer et al.* | |

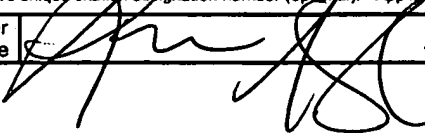
| FOREIGN PATENT DOCUMENTS | | | | | | |
|--------------------------|-----------------------|---|--------------------------------|---|---|----------------|
| Examiner Initials* | Cite No. ¹ | Foreign Patent Document | Publication Date MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear | T ⁶ |
| | | Country Code ³ -Number ⁴ -Kind Code ⁵ (if known) | | | | |
| | | | | | | |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

| NON PATENT LITERATURE DOCUMENTS | | | |
|---------------------------------|--------------------------|---|----------------|
| Examiner Initials* | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | T ² |
| WA | CA | "Silicon Micromachined Waveguides for Millimeter-Wave and Submillimeter-Wave Frequencies" by William R. McGarh, Christopher Walker, Markus Yap, and Yu-Chong Tai, IEE Microwave and Guided Wave Letters, Vol. 3, No. 3, March 1993, Pages 61-63.* | |
| | CB | "Si and SiGe Millimeter-Wave Integrated Circuits" by Peter Russer, IEE Transactions on Microwave Theory and Techniques, Vol. 46, No. 5, May 1998, Pages 590-603* | |
| | CC | Spigel et al., "Impact of Light Illumination and Passivation Layer on Silicon Finite Ground Coplanar Waveguide Transmission Line Properties", October 2000, IEE Transaction on Microwave Theory and Techniques, Volume 48, No. 10, pages 1673-1679.* | |
| | CD | Yang et al., "Characteristics of Trenched Coplanar Waveguide for High Resistivity Si MMIC Applications", May 1998, IEE Transaction on Microwave Theory and Techniques, Volume 46, No. 5, pages 623-631.* | |
| WA | CE | Hu et al., "Characteristics of Trenched Coplanar Waveguide for Si MMIC Applications", June 1997, IEE MTT-Digest, pages 735-738.* | |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. **CITE NO.: Those patent(s) or publication(s) which are marked with an double asterisk (**) next to the Cite No. are not supplied because they were previously cited by or submitted to the Office in a prior application relied upon in this application for an earlier filing date under 35 U.S.C. 120.

¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

| | | | |
|-----------------------|---|--------------------|------------|
| Examiner Signature |  | Date Considered | 02/18/2005 |
|-----------------------|---|--------------------|------------|